

High-Reliability CMOS 32-Word x 8-Bit Static Random-Access Memory

March 1997

Features

- Access Time
 - 610ns..... at $V_{DD} = 5V$
 - 320ns..... at $V_{DD} = 10V$
- No Precharge or Clock Required

Ordering Information

5V	10V	PACK-AGE	TEMP. RANGE	PKG. NO.
CDP1824CD3	CDP1824D3	SBDIP	-55°C to +125°C	D18.3

Description

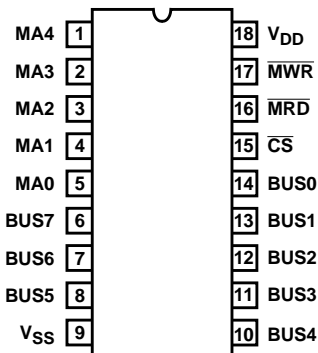
The CDP1824/3 and CDP1824C/3 types are high-reliability CMOS 32-word x 8-bit fully static random-access memories for use in CDP1800-series microprocessor systems. These parts are compatible with the CDP1802 microprocessor and will interface directly without additional components.

The CDP1824/3 is fully decoded and does not require a pre-charge or clocking signal for proper operation. It has common input and output and is operated from a single voltage supply. The \overline{MRD} signal (output disable control) enables the three-state output drivers, and overrides the \overline{MWR} signal. A \overline{CS} input is provided for memory expansion.

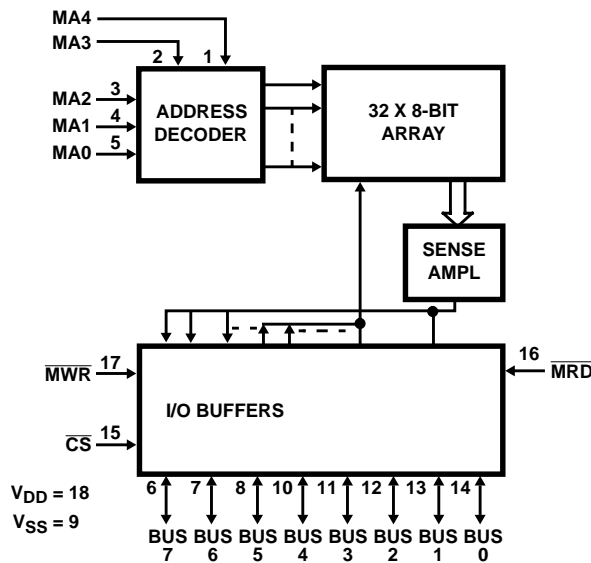
The CDP1824C/3 is functionally identical to the CDP1824/3. The CDP1824/3 has a recommended operating voltage range of 4V to 10.5V, and the CDP1824C/3 has an operating voltage range of 4V to 6.5V.

Pinout

CDP1824/3, CDP1824C/3 (SBDIP)
TOP VIEW



Functional Diagram



OPERATIONAL MODES

FUNCTION	\overline{CS}	\overline{MRD}	\overline{MWR}	DATA PINS STATUS
READ	0	0	X	Output: High/Low Dependent on Data
WRITE	0	1	0	Input: Output Disabled
Not Selected	1	X	X	Output Disabled: High-Impedance State
Standby	0	1	1	Output Disabled: High-Impedance State

Logic 1 = High Logic 0 = Low X = Don't Care

CDP1824/3, CDP1824C/3

Absolute Maximum Ratings

DC Supply Voltage Range, (V_{DD}) (All Voltages Referenced to V_{SS} Terminal)	
CDP1824/3	-0.5V to +11V
CDP1824C/3	-0.5 to +7V
Input Voltage Range, All Inputs	-0.5V to V_{DD} +0.5V
DC Input Current, Any One Input	± 10 mA

Thermal Information

Thermal Resistance (Typical, Note 1)	θ_{JA} ($^{\circ}\text{C}/\text{W}$)	θ_{JC} ($^{\circ}\text{C}/\text{W}$)
SBDIP Package	75	20
Device Dissipation Per Output Transistor		
T_A = Full Package Temperature Range (All Package Types)	100mW	
Operating Temperature Range (T_A)		
Package Type D	-55 $^{\circ}\text{C}$ to +125 $^{\circ}\text{C}$	
Storage Temperature Range (T_{STG})	-65 $^{\circ}\text{C}$ to +150 $^{\circ}\text{C}$	
Lead Temperature (During Soldering)		
At distance 1/16 \pm 1/32 In. (1.59 \pm 0.79mm)		
from case for 10s max	+265 $^{\circ}\text{C}$	

Recommended Operating Conditions T_A = Full Package-Temperature Range. For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

PARAMETER	LIMITS				UNITS
	CDP1824/3		CDP1824C/3		
	MIN	MAX	MIN	MAX	
DC Operating Voltage Range	4	10.5	4	6.5	V
Input Voltage Range	V_{SS}	V_{DD}	V_{SS}	V_{DD}	V

Static Electrical Specifications

PARAMETER	SYMBOL	CONDITIONS			LIMITS				UNITS
		V_O (V)	V_{IN} (V)	V_{DD} (V)	-55 $^{\circ}\text{C}$, +25 $^{\circ}\text{C}$		+125 $^{\circ}\text{C}$		
					MIN	MAX	MIN	MAX	
Quiescent Device Current (Note 1)	I_{DD}	-	0, 5	5	-	50	-	500	μA
		-	0, 10	10	-	500	-	1000	μA
Output Voltage Low-Level (Note 2)	V_{OL}	-	0, 5	5	-	0.1	-	0.2	V
		-		10	-	0.1	-	0.2	V
Output Voltage High-Level (Note 2)	V_{OH}	-	0, 5	5	4.9	-	4.8	-	V
		-	-	10	9.9	-	4.8	-	V
Input Low Voltage	V_{IL}	0.5, 4.5	-	5	-	1.5	-	1.5	V
		1, 9	-	10	-	3	-	-	V
Input High Voltage	V_{IH}	0.5, 4.5	-	5	3.5	-	3.5	-	V
		1, 9	-	10	7	-	7	-	V
Output Low Drive (Sink) Current	I_{OL}	0.4	0, 5	5	4	-	1.5	-	mA
		0.5	0, 10	10	4	-	2.9	-	mA
Output High Drive (Source) Current	I_{OH}	4.6	0, 5	5	-	-1	-	-0.75	mA
		9.5	0, 10	10	-	-2	-	-1.5	mA
Input Current	I_{IN}	Any Input	0, 5	5	-	1	-	5	μA
			0, 10	10	-	1	-	5	μA
Three-State Output Leakage Current	I_{OUT}	0, 5	0, 5	5	-	2	-	5	μA
		0, 10	0, 10	10	-	2	-	5	μA
Input Capacitance	C_{IN}	(Note 2)			-	10	-	10	pF
Output Capacitance	C_{OUT}	(Note 2)			-	15	-	15	pF

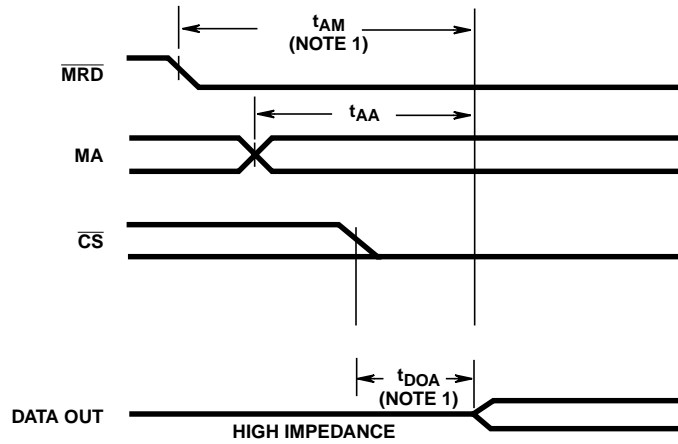
NOTES:

- The CDP1824C/3 meets all 5V Static Electrical Characteristics of the CDP1824/3 except Quiescent Device Current for which the limits are $I_{DD} = 200\mu\text{A}$ at +25 $^{\circ}\text{C}$ /-55 $^{\circ}\text{C}$; $I_{DD} = 1000\mu\text{A}$ at +125 $^{\circ}\text{C}$.
- Guaranteed, but not tested.

CDP1824/3, CDP1824C/3

Read Cycle Dynamic Electrical Specifications Input $t_R, t_F \leq 15\text{ns}$, $C_L = 50\text{pF}$

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS				UNITS
			-55°C, +25°C		+125°C		
		V_{DD} (V)	MIN	MAX	MIN	MAX	
Access Time From Address Change	t_{AA}	5	-	610	-	825	ns
		10	-	320	-	375	ns
Access Time From Chip Select	t_{DOA}	5	-	610	-	825	ns
		10	-	320	-	375	ns
Output Active From MRD	t_{AM}	5	-	610	-	825	ns
		10	-	320	-	375	ns



NOTE:

1. Minimum timing for valid data output longer times will initiate an earlier, but invalid output.

FIGURE 1. READ CYCLE TIMING DIAGRAM

CDP1824/3, CDP1824C/3

Write Cycle Dynamic Electrical Specifications Input $t_R, t_F \leq 15\text{ns}$, $C_L = 50\text{pF}$

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS				UNITS
			-55°C, +25°C		+125°C		
		V _{DD} (V)	(NOTE 1) MIN	MAX	(NOTE 1) MIN	MAX	
Write Pulse Width	t _{WRW}	5	350	-	475	-	ns
		10	180	-	220	-	ns
Data Setup Time	t _{DS}	5	400	-	560	-	ns
		10	190	-	260	-	ns
Data Hold Time	t _{DH}	5	70	-	90	-	ns
		10	35	-	45	-	ns
Chip Select Setup Time	t _{CS}	5	550	-	775	-	ns
		10	340	-	475	-	ns
Address Setup Time	t _{AS}	5	550	-	775	-	ns
		10	340	-	475	-	ns

NOTE:

1. Time required by a device to allow for the indicated function.

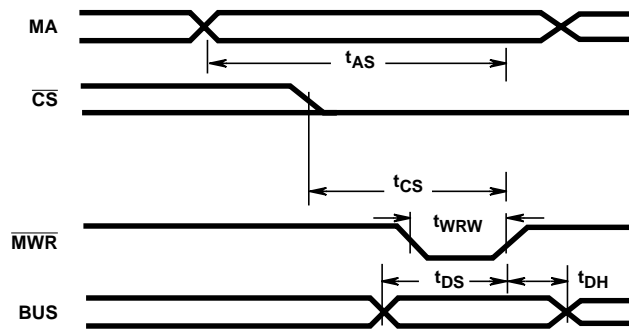


FIGURE 2. WRITE CYCLE TIMING DIAGRAM

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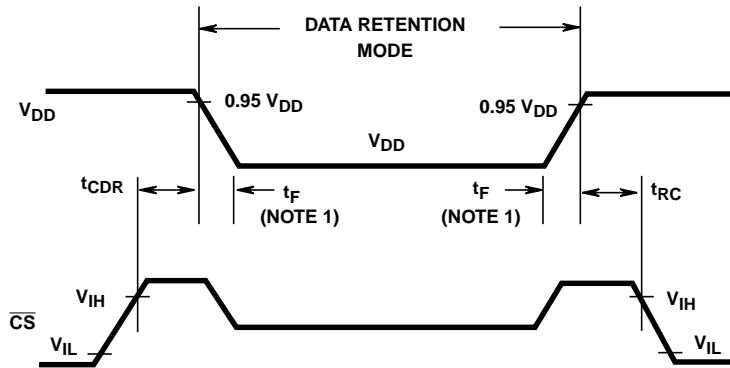
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CDP1824/3, CDP1824C/3

Data Retention Specifications At $T_A = +25^\circ\text{C}$

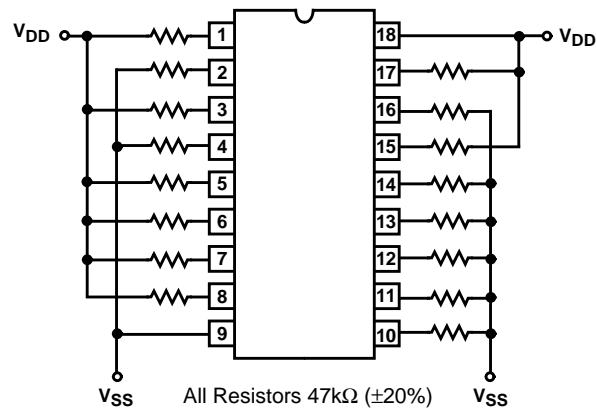
PARAMETER	SYMBOL	TEST CONDITIONS		LIMITS				UNITS
				CDP1824/3		CDP1824C/3		
		V_{DR} (V)	V_{DD} (V)	MIN	MAX	MIN	MAX	
Data Retention Voltage	V_{DR}	-	-	2.5	-	2.5	-	V
Data Retention Quiescent Current	I_{DD}	2.5	-	-	10	-	40	μA
Chip Deselect to Data Retention Time	t_{CDR}	2.5	5	600	-	600	-	ns
		2.5	10	300	-	-	-	ns
Recovery to Normal Operation Time	t_{RC}	2.5	5	600	-	600	-	ns
		2.5	10	300	-	-	-	ns



NOTE: $t_r, t_f > 1\mu\text{s}$.

FIGURE 3. LOW V_{DD} DATA RETENTION WAVEFORMS AND TIMING DIAGRAM

Static Burn-In Circuit



TYPE	V_{DD}	TEMPERATURE	TIME
CDP1824	11V	$+125^\circ\text{C}$	160 Hrs., Min.
CDP1824C	7V	$+125^\circ\text{C}$	160 Hrs., Min.